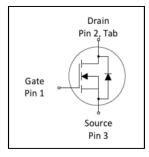


# MOSFET StrongIRFET™

## **Applications**

- UPS and Inverter applications
- Half-bridge and full-bridge topologies
- Resonant mode power supplies
- DC/DC and AC/DC converters
- OR-ing and redundant power switches
- Brushed and BLDC Motor drive applications
- Battery powered circuits

V <sub>DSS</sub>	300V
R <sub>DS(on) typ</sub> .	33m $\Omega$
max	40m $\Omega$
I <sub>D</sub>	50A





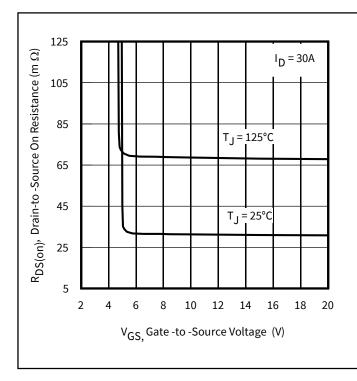
## **Benefits**

- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dv/dt and di/dt Capability
- Pb-Free; RoHS Compliant; Halogen-Free





Base part number	Package Type	Standard Pack	<b>C</b>	Orderable Part Number
base part number	Package Type	Form	Quantity	Orderable Part Number
IRF300P227	TO-247AC	Tube	25	IRF300P227



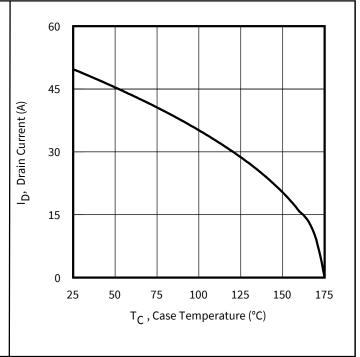


Figure 1 Typical On-Resistance vs. Gate Voltage

Figure 2 Maximum Drain Current vs. Case Temperature

# StrongIRFET™

## IRF300P227



## **Table of Contents**

## **Table of Contents**

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Qualification	Information	.15
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## 1 Parameters

## Table1 Key performance parameters

Parameter	Values	Units
$\overline{V_{DS}}$	300	V
R <sub>DS(on) max</sub>	40	m $Ω$
I <sub>D</sub>	50	A



## 2 Maximum ratings and thermal characteristics

Table 2 Maximum ratings (at T<sub>J</sub>=25°C, unless otherwise specified)

Parameter	Symbol	Conditions	Values	Unit
Continuous Drain Current	I <sub>D</sub>	$T_C = 25^{\circ}C, V_{GS} @ 10V$	50	
Continuous Drain Current	I <sub>D</sub>	$T_C = 100^{\circ}C, V_{GS} @ 10V$	35	Α
Pulsed Drain Current ①	I <sub>DM</sub>	T <sub>C</sub> = 25°C	189	
Maximum Power Dissipation	P <sub>D</sub>	$T_C = 25$ °C	313	W
Linear Derating Factor		$T_C = 25^{\circ}C$	2.1	W/°C
Peak Diode Recovery ③	dv/dt	$T_J = 175$ °C, $I_S = 20A$ , $V_{DS} = 150V$	6.0	V/ns
Gate-to-Source Voltage	$V_{GS}$	-	± 20	V
Operating Junction and Storage Temperature Range	T <sub>J</sub> T <sub>STG</sub>	-	-55 to + 175	°C
Soldering Temperature, for 10 seconds (1.6mm from case)	-	-	300	
Mounting Torque, 6-32 or M3 Screw	-	-	10 lbf·in (1.1 N·m)	-

### **Table 3** Thermal characteristics

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit
Junction-to-Case ⑦	$R_{ heta JC}$	T」approximately 90°C	-	-	0.48	
Case-to-Sink, Flat Greased Surface	$R_{\theta CS}$	-	-	0.24	-	°C/W
Junction-to-Ambient	$R_{ heta JA}$	-	-	-	40	

### Table 4 Avalanche characteristics

Parameter	Symbol	Values	Unit
Single Pulse Avalanche Energy ②	Eas (Thermally limited)	455	
Single Pulse Avalanche Energy Tested Value ®	E <sub>AS (tested)</sub>	451	mJ
Avalanche Current ①	I <sub>AR</sub>		Α
Repetitive Avalanche Energy ①	E <sub>AR</sub>	See Fig 16, 17, 23a, 23b	mJ

### **Notes:**

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 1mH,  $R_G = 50\Omega$ ,  $I_{AS} = 30$ A,  $V_{GS} = 10V$ .
- ④ Pulse width  $\leq$ 400 $\mu$ s; duty cycle  $\leq$ 2%.
- $\odot$  C<sub>oss</sub> eff. (TR) is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- ©  $C_{oss}$  eff. (ER) is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- $\mathcal{D}$   $R_{\theta}$  is measured at  $T_{J}$  approximately 90°C.
- ® This value determined from sample failure population, starting  $T_J = 25^{\circ}\text{C}$ , L = 1 mH,  $R_G = 50 \Omega$ ,  $I_{AS} = 30 \text{A}$ ,  $V_{GS} = 10 \text{V}$ .



## 3 Electrical characteristics

**Table 5** Static characteristics

Parameter	Symbol Conditions		Values			Unit
Parameter	Syllibot	Conditions	Min.	Тур.	Max.	Oilit
Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V$ , $I_D = 1mA$	300	-	-	V
Breakdown Voltage Temp. Coefficient	$\Delta V_{(BR)DSS}/\Delta T_J$	Reference to 25°C, I <sub>D</sub> = 1.0mA ①	-	0.12	ı	V/°C
Static Drain-to-Source On-Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10V, I_D = 30A$	-	33	40	mΩ
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_{D} = 270 \mu A$	2.0	-	4.0	V
	I <sub>DSS</sub>	$V_{DS} = 240V, V_{GS} = 0V$	-	-	10	
Drain-to-Source Leakage Current		$V_{DS} = 240V, V_{GS} = 0V, T_{J} = 125^{\circ}C$	-	-	300	μΑ
Gate-to-Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = 20V	-	-	100	nA
Gate Resistance	$R_{G}$		-	2.7	-	Ω

## Table 6 Dynamic characteristics

Parameter	Cumbal	Conditions		Values		Unit
Parameter	Symbol	Conditions	Min.	Тур.	Max.	Onit
Forward Trans conductance	gfs	$V_{DS} = 50V, I_{D} = 30A$	62	-	-	S
Total Gate Charge	Qg		-	71	107	
Gate-to-Source Charge	$Q_{gs}$	$I_D = 30A$ $V_{DS} = 150V$	-	28	-	nC
Gate-to-Drain Charge	Q <sub>gd</sub>	$V_{DS} = 130V$ $V_{GS} = 10V$	-	13	-	IIC
Total Gate Charge Sync. (Qg– Qgd)	$Q_{sync}$		-	58	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 150V	-	16	-	
Rise Time	t <sub>r</sub>	$I_D = 30A$	-	43	-	
Turn-Off Delay Time	$t_{d(off)}$	$R_G = 2.7\Omega$	-	51	-	ns
Fall Time	t <sub>f</sub>	V <sub>GS</sub> = 10V	-	28	-	
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0V$	-	4893	-	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = 50V	-	425	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz, See Fig.7	-	6.6	-	pF
Effective Output Capacitance (Energy Related)	Coss eff.(ER)	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 240V ⑥	-	282	-	Γ'
Output Capacitance (Time Related)	Coss eff.(TR)	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 240V  $	-	485	-	

Table 7 Reverse Diode

Parameter	Symbol	Conditions	Values			Unit	
rai ailletei Syllibot		Conditions	Min.	Тур.	Max.	Oilit	
Continuous Source Current (Body Diode)	Is	MOSFET symbol showing the	-	-	50	Α	
Pulsed Source Current (Body Diode) ①	I <sub>SM</sub>	integral reverse p-n junction diode.	-	-	189	Α	
Diode Forward Voltage	$V_{SD}$	$T_J = 25^{\circ}C$ , $I_S = 30A$ , $V_{GS} = 0V$ 4	-	-	1.2	V	
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25°C	-	140	-	ns	
Reverse Recovery Time	L <sub>rr</sub>	Crr	T <sub>J</sub> = 125°C	-	199	-	113
Reverse Recovery Charge	0	$T_J = 25^{\circ}C$ $V_{DD} = 150V$ $I_F = 30A$ ,	-	313	-	nC	
Neverse Necovery Charge	Q <sub>rr</sub>	$T_J = 125^{\circ}C$ di/dt = 100A/ $\mu$ s 4	-	811	-	110	
Reverse Recovery Current	lanu	T <sub>J</sub> = 25°C	-	3.1	-	Α	
	I <sub>RRM</sub>	T <sub>J</sub> = 125°C	-	5.5	ı	A	



# 4 Electrical characteristic diagrams

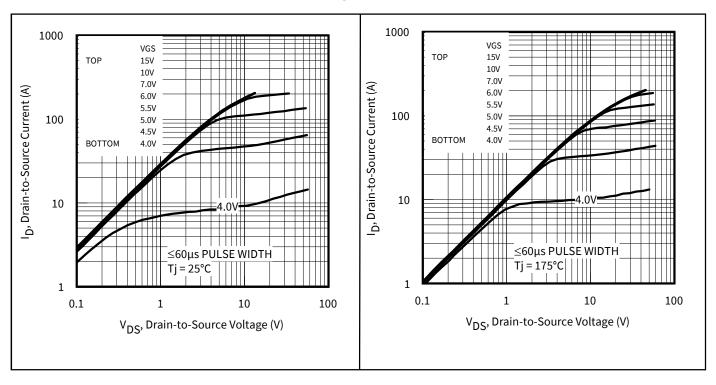


Figure 3 Typical Output Characteristics

Figure 4 Typical Output Characteristics

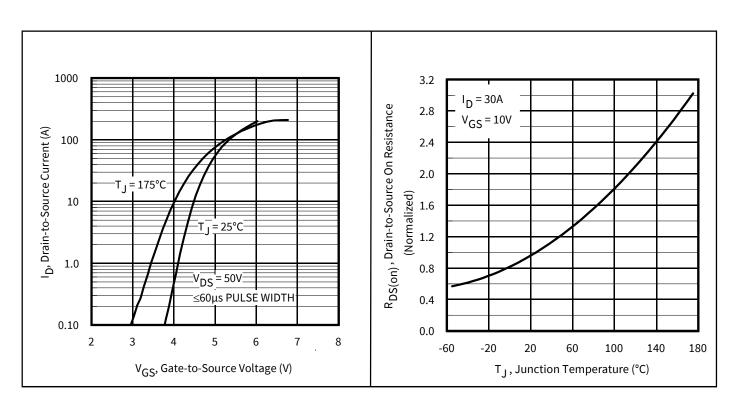


Figure 5 Typical Transfer Characteristics

Figure 6 Normalized On-Resistance vs. Temperature



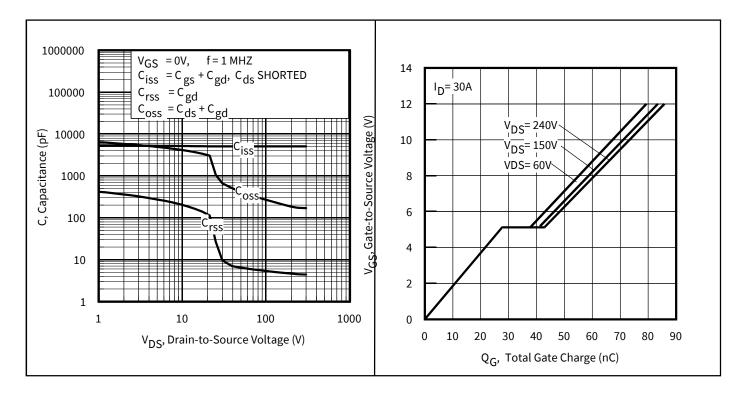


Figure 7 Typical Capacitance vs. Drain-to-Source Figure 8 Typical Gate Charge vs. Gate-to-Source Voltage

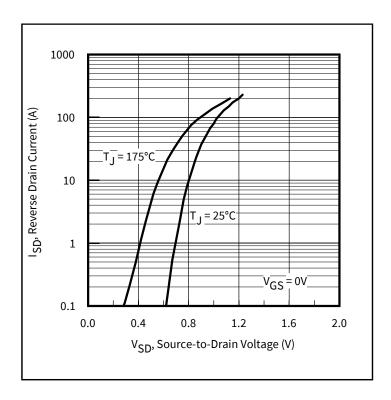


Figure 9 Typical Source-Drain Diode Forward Voltage



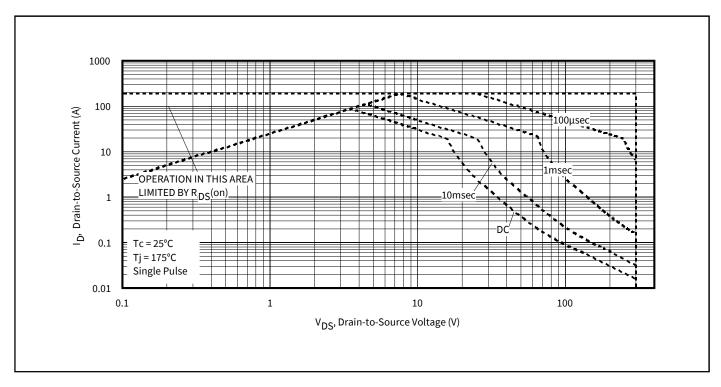


Figure 10 Maximum Safe Operating Area

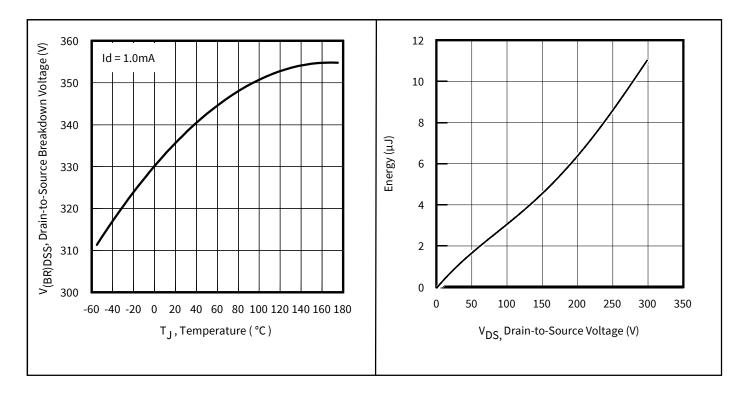


Figure 11 Drain-to-Source Breakdown Voltage

Figure 12 Typical Coss Stored Energy



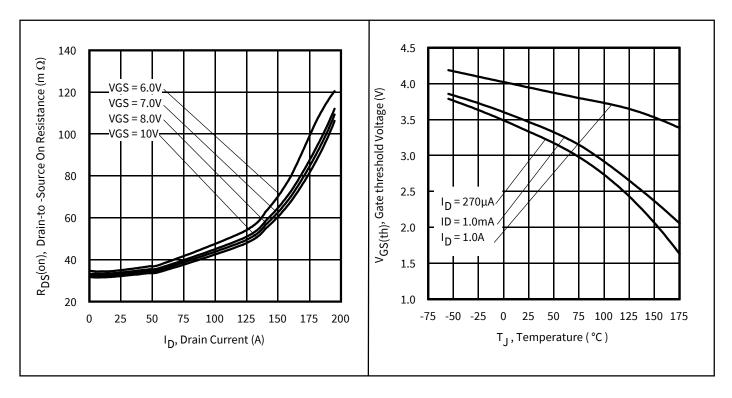


Figure 13 Typical On-Resistance vs. Drain Current

Figure 14 Threshold Voltage vs. Temperature

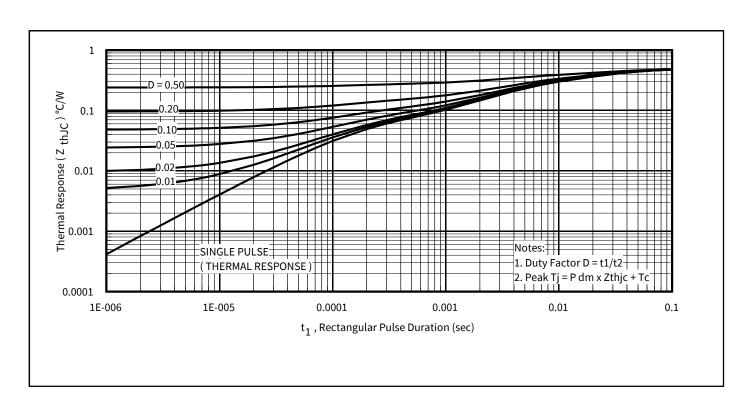


Figure 15 Maximum Effective Transient Thermal Impedance, Junction-to-Case



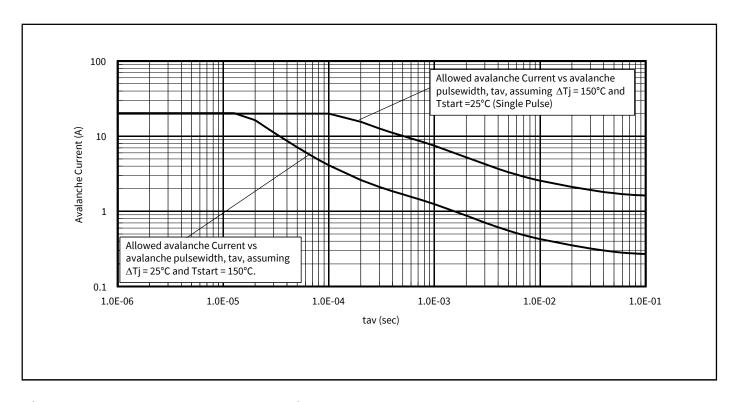


Figure 16 **Avalanche Current vs. Pulse Width** 

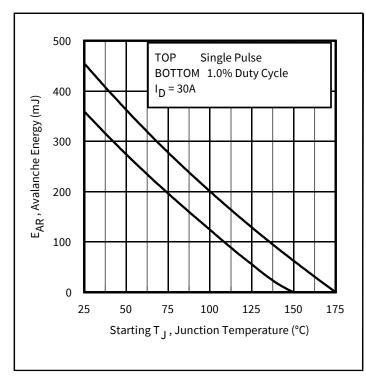


Figure 17 Maximum Avalanche Energy vs. **Temperature** 

### Notes on Repetitive Avalanche Curves, Figures 16, 17: (For further info, see AN-1005 at www.infineon.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>imax</sub>. This is validated for every

- 2. Safe operation in Avalanche is allowed as long as T<sub>imax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche). 6. I<sub>av</sub> = Allowable avalanche current.
- 7. DT = Allowable rise in junction temperature, not to exceed  $T_{jmax}$ (assumed as 25°C in Figure 15, 16).

t<sub>av</sub> = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av}) = Transient thermal resistance, see Figures 14)$ 

PD (ave) = 1/2 (  $1.3 \cdot BV \cdot I_{av}$ ) =  $\Delta T / Z_{thJC}$ 

 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$ 

 $E_{AS (AR)} = P_{D (ave)} \cdot t_{av}$ 



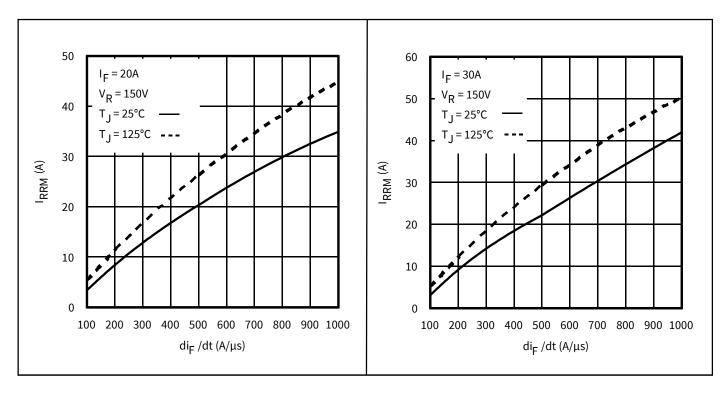


Figure 18 Typical Recovery Current vs. dif/dt

Figure 19 Typical Recovery Current vs. dif/dt

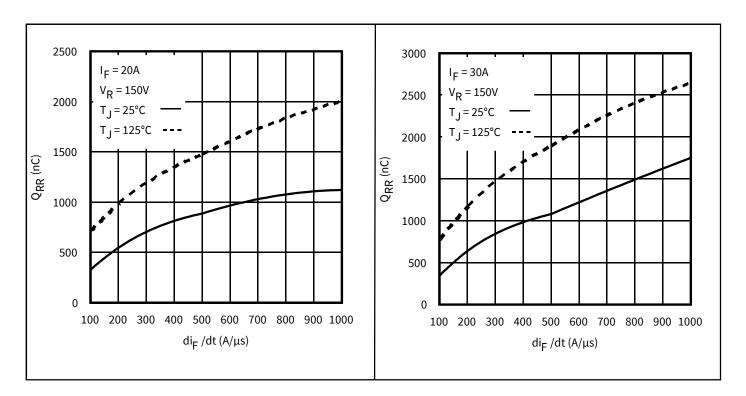


Figure 20 Typical Stored Charge vs. dif/dt

Figure 21 Typical Stored Charge vs. dif/dt



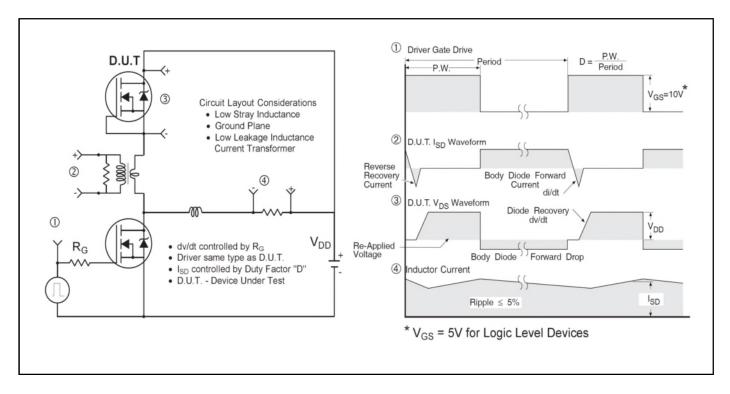


Figure 22 Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET™ Power MOSFETs

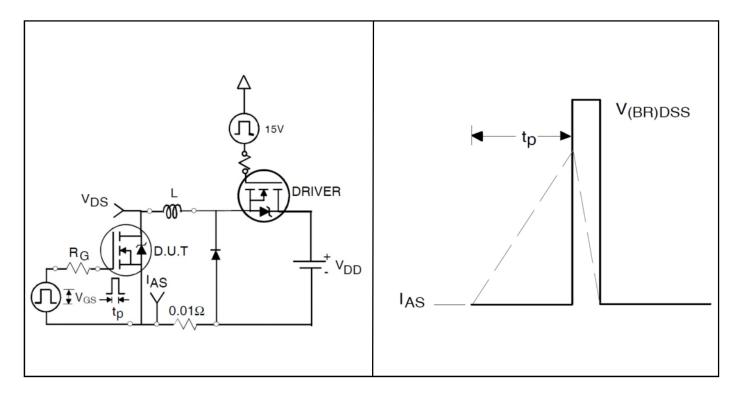


Figure 23a Unclamped Inductive Test Circuit

Figure 23b Unclamped Inductive Waveforms



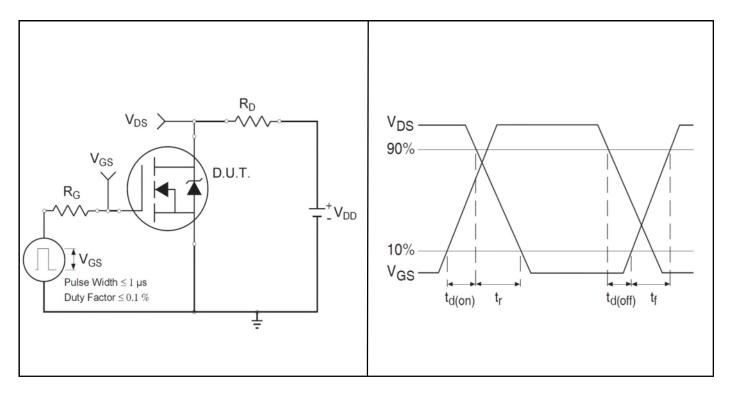


Figure 24a Switching Time Test Circuit

Figure 24b Switching Time Waveforms

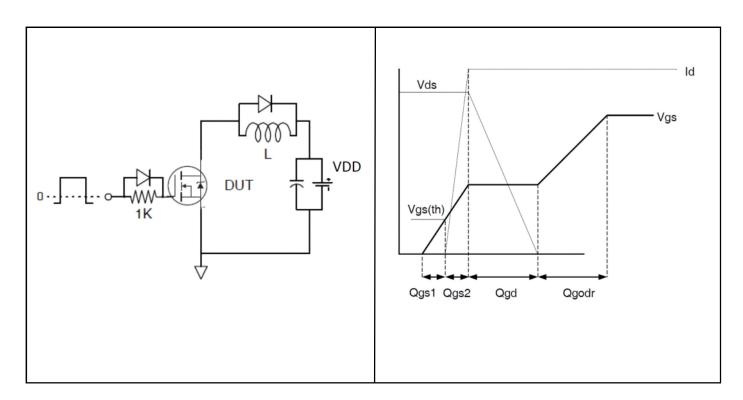


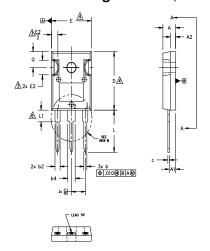
Figure 25a Gate Charge Test Circuit

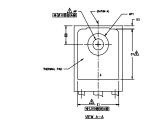
Figure 25b Gate Charge Waveform



### **Package Information** 5

### TO-247AC Package Outline (Dimensions are shown in millimeters (inches))









- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M 1994.
- DIMENSIONS ARE SHOWN IN INCHES.
- CONTOUR OF SLOT OPTIONAL.
- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS D1 & E1.
- LEAD FINISH UNCONTROLLED IN L1.
- $\ensuremath{\mathrm{OP}}$  TO HAVE A MAXIMUM DRAFT ANGLE OF 1.5  $^{\circ}$  TO THE TOP OF THE PART WITH A MAXIMUM HOLE DIAMETER OF .154 INCH.
- OUTLINE CONFORMS TO JEDEC OUTLINE TO-247AC.

	DIMENSIONS				
SYMBOL	INCHES		MILLIM	ETERS	
	MIN.	MAX.	MIN.	MAX.	NOTES
A	.183	.209	4.65	5.31	
A1	.087	.102	2.21	2.59	
A2	.059	.098	1.50	2.49	
b	.039	.055	0.99	1.40	
b1	.039	.053	0.99	1.35	
b2	.065	.094	1.65	2.39	
b3	.065	.092	1.65	2.34	
b4	.102	.135	2.59	3.43	
b5	.102	.133	2.59	3.38	
С	.015	.035	0.38	0.89	
c1	.015	.033	0.38	0.84	
D	.776	.815	19.71	20.70	4
D1	.515	-	13.08	-	5
D2	.020	.053	0.51	1.35	
E	.602	.625	15.29	15.87	4
E1	.530	-	13.46	-	
E2	.178	.216	4.52	5.49	
e	.215	BSC	5.46	BSC	]
Øk	.0	10	0.	25	
L	.559	.634	14.20	16.10	
L1	.146	.169	3.71	4.29	
ØΡ	.140	.144	3.56	3.66	
øP1	-	.291	-	7.39	
Q	.209	.224	5.31	5.69	
S	.217	BSC	5.51	BSC	

### LEAD ASSIGNMENTS

HEX	FET
1	GATE
2	DRAIN

3.- SOURCE 4.- DRAIN

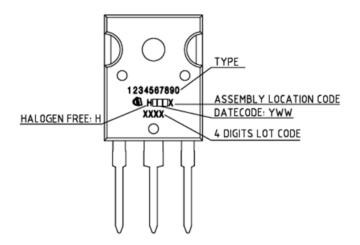
### IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

### DIODES

- 1.- ANODE/OPEN
- 2.— CATHODE 3.— ANODE

## **TO-247AC Part Marking Information**



TO-247AC package is not recommended for Surface Mount Application.



# **6** Qualification Information

**Qualification Information** 

Qualification Level	Industrial (per JEDEC JESD47F) †	
Moisture Sensitivity Level	TO-247AC	N/A
RoHS Compliant		Yes

<sup>†</sup> Applicable version of JEDEC standard at the time of product release.

# StrongIRFET™

## IRF300P227



# **Revision History**

## Major changes since the last revision

Page or Reference	Revision	Date	Description of changes	
All pages	1.0	2017-02-27	• First release data sheet.	
All pages	1.1	2017-07-20	<ul> <li>Updated @ 25c = 20A on Avalanche Current vs. Pulse Width fig 16 on page 10</li> <li>Added DV/DT = 6V/ns, Di/Dt = 1000A/us, Tjmax = 175C, VDS = 150V, Id = 20A on page 4</li> <li>Added IRRM = 5.5A @ 125c on page 5.</li> </ul>	
All pages	2.0	2017-11-14	First release final datasheet.	
All pages	2.1	2020-01-07	Update from "IR MOSFT/StrongIRFET <sup>TM</sup> " to "StrongIRFET <sup>TM</sup> " -all pages Update Package picture –page1	
Page 14	2.2	2024-11-26	Updated Part marking –page 14	

## StrongIRFET™

### IRF300P227



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